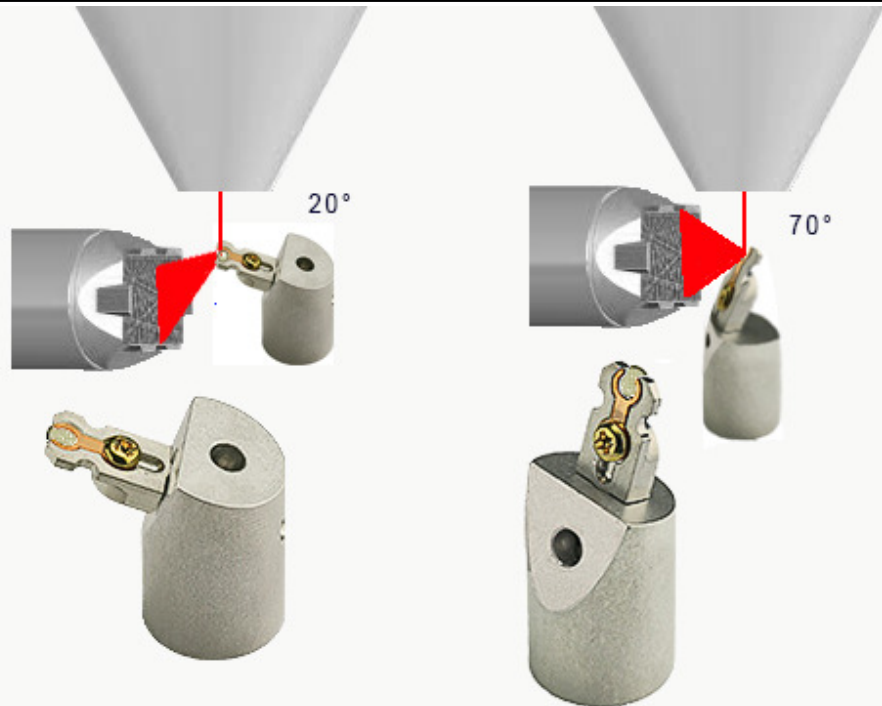


EBSA analysis is a powerful microstructural crystallographic characterisation technique for crystalline or polycrystalline materials. Standard EBSA analysis on bulk samples and surfaces is performed on high-tilt samples (typically 70° from horizontal). The EBSA pattern reveals the crystal orientation and in polycrystalline materials the variation of orientation amongst the crystals. For optimum EBSA results, deformation free, polished surfaces are needed.

Transmission EBSA analysis is only possible on (very) thin TEM samples suspended on a TEM grid or on a TEM lamella attached to an FIB grid. EBSA analysis on thin samples can be performed in backscatter mode at 70° tilt (from horizontal) or transmission mode at 20° (from horizontal). For transmission EBSA or t-EBSA it is imperative that transmitted electrons can reach the EBSA detector without any obstruction.

Our t-EBSA holders are specifically designed to generate transmission Kikuchi patterns. The transmission EBSA holders include an opening of 2mm Ø in the base. The top is formed by a fork-shaped phosphor-bronze clip which clamps the TEM or FIB grid. Transmission EBSA imaging and analysis is possible over the 2mm Ø area.

EBSA Sample Holders for TEM & FIB Grids



The t-EBSA holders are available with 1 or 3 TEM grid capacity.



S738 t-EBSA holder for three (3) TEM/FIB lift-out grids [standard pin](#)

S739 t-EBSA holder for one (1) TEM/FIB lift-out grid [standard pin](#)

S740 3x replacement t-EBSA TEM grid clips plus 3x M2 3mm brass screws



S741 t-EBSA holder kit 20°/70° for three TEM/FIB lift-out grids [standard pin](#)

S742 t-EBSA holder kit 20°/70° for single TEM/FIB lift-out grid [standard pin](#)



S743 t-EBSA holder kit 20°/70° for three TEM/FIB lift-out grids [M4](#)

S744 t-EBSA holder kit 20°/70° for single TEM/FIB lift-out grid [M4](#)